



IN THE UNITED STATES

PATENT AND TRADEMARK OFFICE

APPLICANT(S): Steven W. Meeks & Rusmin Kudinar

SERIAL NO.: 09/347,622

FILING DATE: July 2, 1999

TITLE: System for Simultaneously Measuring Thin Film Layer Thickness, Reflectivity, Roughness, Surface Profile and Magnetic Pattern

EXAMINER: T. Nguyen

GROUP ART UNIT: 2877

ATTY. DKT. NO.: 20830-04304; Case 4304 US

TECHNOLOGY CENTER 280C

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CERTIFICATE OF MAILING

I hereby certify that this correspondence, including the enclosures identified above, is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231 on the date shown below.

Dated: 10/29/2002

By:

Lawrence E. Carter, Reg. No.: P-51,532

COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

RESPONSE AND AMENDMENT "C"
UNDER 37 CFR §1.111

Sir:

In response to the Office Action dated July 29, 2002, Applicants submit the following

Amendment and Remarks.

11/06/2002 DTESSEH1 00000043 192555 09347622

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